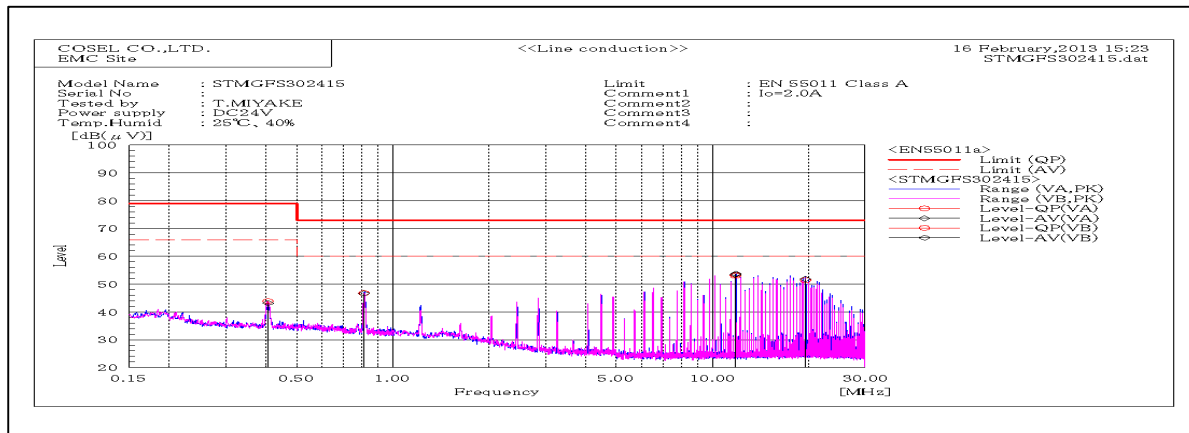
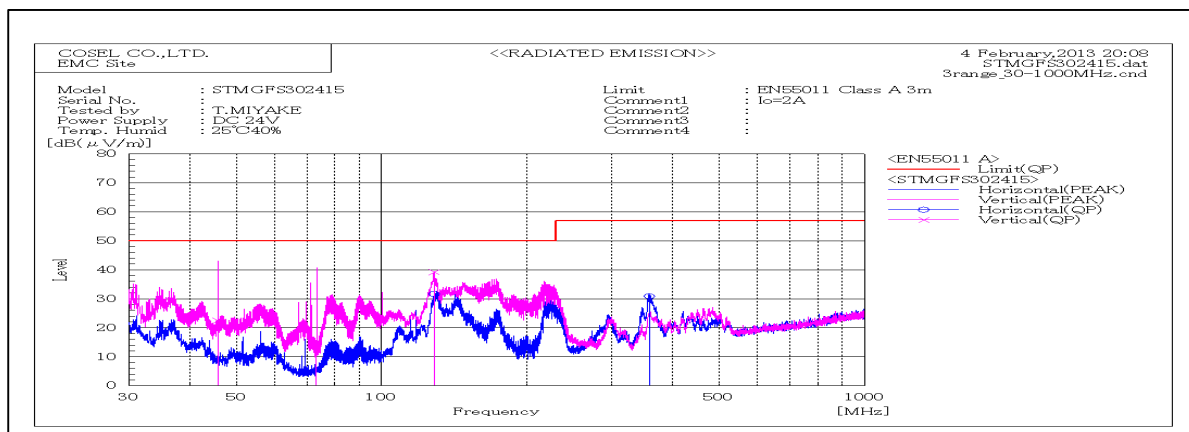


DATA SHEET		Date	18-Feb-13
Model	STMGFS302415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



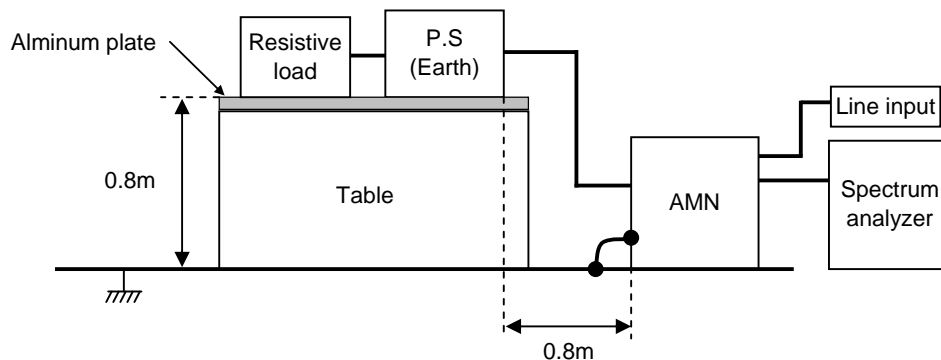
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.40729		VB	23.8	23	20.1	43.9	43.1	79	66	35.1	22.9	Pass	
0.81325		VA	26.7	26.6	20.1	46.8	46.7	73	60	26.2	13.3	Pass	
11.79885		VB	32.2	32.6	20.8	53	53.4	73	60	20	6.6	Pass	
11.79745		VA	32.5	32.8	20.9	53.4	53.7	73	60	19.6	6.3	Pass	
19.5239		VB	30.2	30.6	21.2	51.4	51.8	73	60	21.6	8.2	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP					
45.889	V	Stable	43.2		-20.8	22.4	50	27.6	Pass	108	332	
73.245	V	Stable	34.7		-20.3	14.4	50	35.6	Pass	103	7	
128.496	V	Stable	56.6		-17.4	39.2	50	10.8	Pass	103	336	
128.508	H	Stable	51.2		-19.6	31.6	50	18.4	Pass	150	240	
358.597	H	Stable	43.8		-12.9	30.9	57	26.1	Pass	103	76	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

